#### RD53A Emulator Status and Plans

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#### RD53A

- Development chip for HL-LHC
- Used to test 65 nm for ATLAS and CMS
  - Radiation tolerance
  - High data rate capability
- Multiple variations on analog front ends for comparison purposes
- Manufacture in October





#### Collaborators

- Joe Mayer began work on the emulator (graduated)
  - Thesis available: https://cds.cern.ch/record/2198312?ln=en
- Logan Adams Graduate student
- Dustin Werran Graduate student
- Douglas Smith Undergraduate student
- Yangming Ke Undergraduate student
- Advised by
  - Shih-Chieh Hsu (UW Physics)
  - Scott Hauck (UW EE) FPGA professor
- Working with Timon and Maurice and others to ensure emulator project is as useful to all as possible

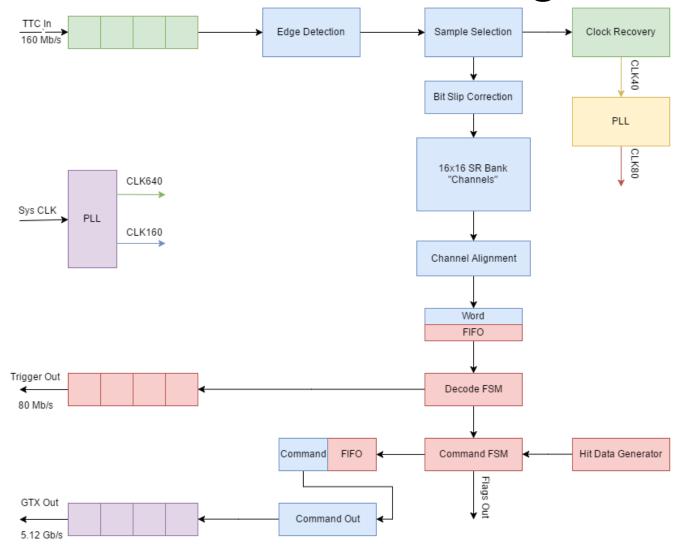


### Current Implementation

- Simulation model of RD53A emulator working
  - Mostly up to specification
- "DAQ" system emulator
  - Test communication
  - Useful before real next-gen DAQ systems available
- Command module
  - Communicate between computer host and "DAQ"

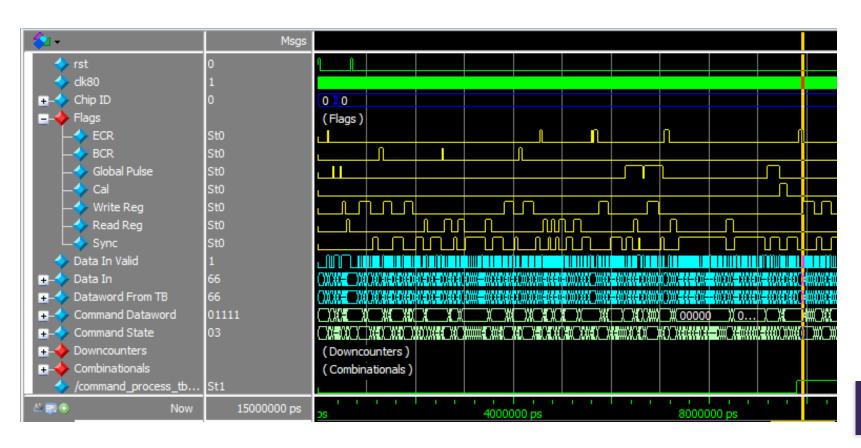


### **Emulator Block Diagram**





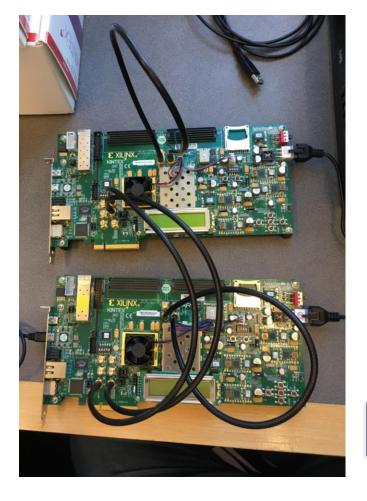
#### **Command Process Wave**





### **Current Testing**

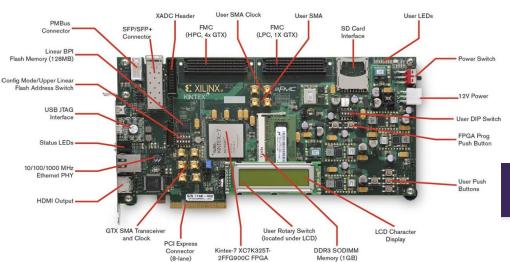
- Two Xilinx KC705 FPGA Development Boards
- Limited to SMA (available on the boards)
- DisplayPort testing when available





### Development Plans

- Hit Data Emulation
- Global registers
- 5 Gig Links working on board
- Layout DisplayPort daughter card and spin
  - KC705 expansion
  - Possibly designed by OSU
- Testing with RCE as DAQ





#### Feedback

- How can we make this as useful as possible?
  - What do you want to see implemented?
- Contact us if you are interested in the emulator.
  - All feedback on user experience is helpful.

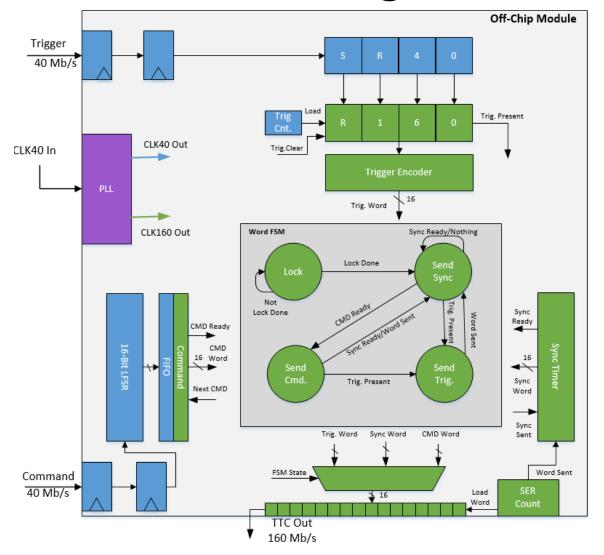
Thanks!



# Backup Slides



# "DAQ" Diagram





## System Test

- "DAQ-lite" designed to create/send TTC stream
- Testing system on KC705 FPGA with Host
- SMA Cables used for high speed communication (Not a system dependency)
- Capable of fully testing I/O and digital logic blocks
  - One-shot, continuous trigger, etc.



